Se	arcn No	otes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/039,852	SHIH ET AL.	
Examiner	Art Unit	-
John P. Trimmings	2138	

	SEARCHED		
Class	Subclass	Date	Examiner
	,		
	<u></u>		· .
		•	

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
714	733	3/13/2006	JPT
,			

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
NPL Search: test circuit register pattern multiplexer.	3/13/2006	JPT
Dble Patent Search: Negative.	3/13/2006	JPT
Class Search: 714/726,724,727,729,733,734,30,31. Text search strategy attached.	3/13/2006	JPT
	·	١
	·	